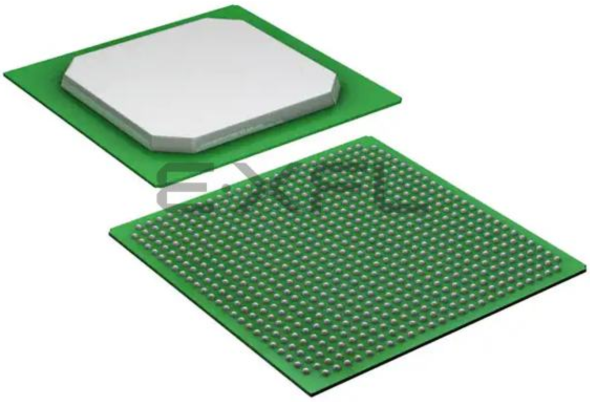
Intel - EP4CGX110DF27I7N Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Active
Number of LABs/CLBs	6839
Number of Logic Elements/Cells	109424
Total RAM Bits	5621760
Number of I/O	393
Number of Gates	-
Voltage - Supply	1.16V ~ 1.24V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	672-BGA
Supplier Device Package	672-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep4cgx110df27i7n

A DC signal is equivalent to 100% duty cycle. For example, a signal that overshoots to 4.3 V can only be at 4.3 V for 65% over the lifetime of the device; for a device lifetime of 10 years, this amounts to 65/10ths of a year.

Table 1–2. Maximum Allowed Overshoot During Transitions over a 10-Year Time Frame for Cyclone IV Devices

Symbol	Parameter	Condition (V)	Overshoot Duration as % of High Time	Unit
V_i	AC Input Voltage	$V_I = 4.20$	100	%
		$V_I = 4.25$	98	%
		$V_I = 4.30$	65	%
		$V_I = 4.35$	43	%
		$V_I = 4.40$	29	%
		$V_I = 4.45$	20	%
		$V_I = 4.50$	13	%
		$V_I = 4.55$	9	%
		$V_I = 4.60$	6	%

Figure 1–1 shows the methodology to determine the overshoot duration. The overshoot voltage is shown in red and is present on the input pin of the Cyclone IV device at over 4.3 V but below 4.4 V. From Table 1–2, for an overshoot of 4.3 V, the percentage of high time for the overshoot can be as high as 65% over a 10-year period. Percentage of high time is calculated as ([delta T]/T) × 100. This 10-year period assumes that the device is always turned on with 100% I/O toggle rate and 50% duty cycle signal. For lower I/O toggle rates and situations in which the device is in an idle state, lifetimes are increased.

Figure 1–1. Cyclone IV Devices Overshoot Duration

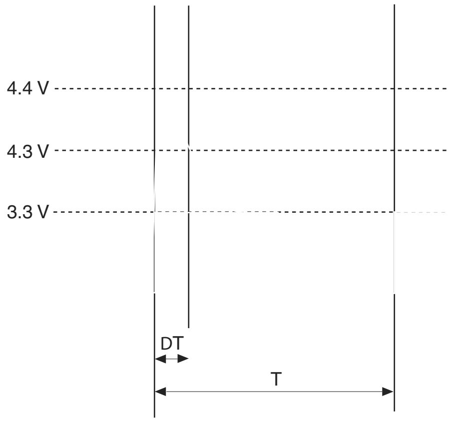


Table 1–3. Recommended Operating Conditions for Cyclone IV E Devices *(1), (2)* (Part 2 of 2)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
I_{Diode}	Magnitude of DC current across PCI-clamp diode when enable	—	—	—	10	mA

Notes to Table 1–3:

(1) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades.

(2) V_{CCIO} for all I/O banks must be powered up during device operation. All `VCCA` pins must be powered to 2.5 V (even when PLLs are not used) and must be powered up and powered down at the same time.

(3) V_{CC} must rise monotonically.

(4) V_{CCIO} powers all input buffers.

(5) The POR time for Standard POR ranges between 50 and 200 ms. Each individual power supply must reach the recommended operating range within 50 ms.

(6) The POR time for Fast POR ranges between 3 and 9 ms. Each individual power supply must reach the recommended operating range within 3 ms.

Table 1–4. Recommended Operating Conditions for Cyclone IV GX Devices (Part 1 of 2)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{CCINT} *(3)*	Core voltage, PCIe hard IP block, and transceiver PCS power supply	—	1.16	1.2	1.24	V
V_{CCA} *(1), (3)*	PLL analog power supply	—	2.375	2.5	2.625	V
V_{CCD_PLL} *(2)*	PLL digital power supply	—	1.16	1.2	1.24	V
V_{CCIO} *(3), (4)*	I/O banks power supply for 3.3-V operation	—	3.135	3.3	3.465	V
	I/O banks power supply for 3.0-V operation	—	2.85	3	3.15	V
	I/O banks power supply for 2.5-V operation	—	2.375	2.5	2.625	V
	I/O banks power supply for 1.8-V operation	—	1.71	1.8	1.89	V
	I/O banks power supply for 1.5-V operation	—	1.425	1.5	1.575	V
	I/O banks power supply for 1.2-V operation	—	1.14	1.2	1.26	V
V_{CC_CLKIN} *(3), (5), (6)*	Differential clock input pins power supply for 3.3-V operation	—	3.135	3.3	3.465	V
	Differential clock input pins power supply for 3.0-V operation	—	2.85	3	3.15	V
	Differential clock input pins power supply for 2.5-V operation	—	2.375	2.5	2.625	V
	Differential clock input pins power supply for 1.8-V operation	—	1.71	1.8	1.89	V
	Differential clock input pins power supply for 1.5-V operation	—	1.425	1.5	1.575	V
	Differential clock input pins power supply for 1.2-V operation	—	1.14	1.2	1.26	V
V_{CCH_GXB}	Transceiver output buffer power supply	—	2.375	2.5	2.625	V

Table 1–4. Recommended Operating Conditions for Cyclone IV GX Devices (Part 2 of 2)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{CCA_GXB}	Transceiver PMA and auxiliary power supply	—	2.375	2.5	2.625	V
V_{CCL_GXB}	Transceiver PMA and auxiliary power supply	—	1.16	1.2	1.24	V
V_I	DC input voltage	—	–0.5	—	3.6	V
V_O	DC output voltage	—	0	—	V_{CCIO}	V
T_J	Operating junction temperature	For commercial use	0	—	85	°C
		For industrial use	–40	—	100	°C
t_{RAMP}	Power supply ramp time	Standard power-on reset (POR) *(7)*	50 µs	—	50 ms	—
		Fast POR *(8)*	50 µs	—	3 ms	—
I_{Diode}	Magnitude of DC current across PCI-clamp diode when enabled	—	—	—	10	mA

Notes to Table 1–4:

(1) All `VCCA` pins must be powered to 2.5 V (even when PLLs are not used) and must be powered up and powered down at the same time.

(2) You must connect V_{CCD_PLL} to V_{CCINT} through a decoupling capacitor and ferrite bead.

(3) Power supplies must rise monotonically.

(4) V_{CCIO} for all I/O banks must be powered up during device operation. Configurations pins are powered up by V_{CCIO} of I/O Banks 3, 8, and 9 where I/O Banks 3 and 9 only support V_{CCIO} of 1.5, 1.8, 2.5, 3.0, and 3.3 V. For fast passive parallel (FPP) configuration mode, the V_{CCIO} level of I/O Bank 8 must be powered up to 1.5, 1.8, 2.5, 3.0, and 3.3 V.

(5) You must set V_{CC_CLKIN} to 2.5 V if you use `CLKIN` as a high-speed serial interface (HSSI) `refclk` or as a `DIFFCLK` input.

(6) The `CLKIN` pins in I/O Banks 3B and 8B can support single-ended I/O standard when the pins are used to clock left PLLs in non-transceiver applications.

(7) The POR time for Standard POR ranges between 50 and 200 ms. V_{CCINT}, V_{CCA}, and V_{CCIO} of I/O Banks 3, 8, and 9 must reach the recommended operating range within 50 ms.

(8) The POR time for Fast POR ranges between 3 and 9 ms. V_{CCINT}, V_{CCA}, and V_{CCIO} of I/O Banks 3, 8, and 9 must reach the recommended operating range within 3 ms.

ESD Performance

This section lists the electrostatic discharge (ESD) voltages using the human body model (HBM) and charged device model (CDM) for Cyclone IV devices general purpose I/Os (GPIOs) and high-speed serial interface (HSSI) I/Os. Table 1–5 lists the ESD for Cyclone IV devices GPIOs and HSSI I/Os.

Table 1–5. ESD for Cyclone IV Devices GPIOs and HSSI I/Os

Symbol	Parameter	Passing Voltage	Unit
V_{ESDHBM}	ESD voltage using the HBM (GPIOs) *(1)*	± 2000	V
	ESD using the HBM (HSSI I/Os) *(2)*	± 1000	V
V_{ESDCDM}	ESD using the CDM (GPIOs)	± 500	V
	ESD using the CDM (HSSI I/Os) *(2)*	± 250	V

Notes to Table 1–5:

(1) The passing voltage for EP4CGX15 and EP4CGX30 row I/Os is ±1000V.

(2) This value is applicable only to Cyclone IV GX devices.

DC Characteristics

This section lists the I/O leakage current, pin capacitance, on-chip termination (OCT) tolerance, and bus hold specifications for Cyclone IV devices.

Supply Current

The device supply current requirement is the minimum current drawn from the power supply pins that can be used as a reference for power size planning. Use the Excel-based early power estimator (EPE) to get the supply current estimates for your design because these currents vary greatly with the resources used. Table 1–6 lists the I/O pin leakage current for Cyclone IV devices.

Table 1–6. I/O Pin Leakage Current for Cyclone IV Devices (1), (2)

Symbol	Parameter	Conditions	Device	Min	Typ	Max	Unit
I_I	Input pin leakage current	V_I = 0 V to $V_{CCIOMAX}$	—	–10	—	10	µA
I_{OZ}	Tristated I/O pin leakage current	V_O = 0 V to $V_{CCIOMAX}$	—	–10	—	10	µA

Notes to Table 1–6:

(1) This value is specified for normal device operation. The value varies during device power-up. This applies for all V_{CCIO} settings (3.3, 3.0, 2.5, 1.8, 1.5, and 1.2 V).

(2) The 10 µA I/O leakage current limit is applicable when the internal clamping diode is off. A higher current can be observed when the diode is on.

Bus Hold

The bus hold retains the last valid logic state after the source driving it either enters the high impedance state or is removed. Each I/O pin has an option to enable bus hold in user mode. Bus hold is always disabled in configuration mode.

Table 1–7 lists bus hold specifications for Cyclone IV devices.

Table 1–7. Bus Hold Parameter for Cyclone IV Devices (Part 1 of 2) (1)

Parameter	Condition	V_{CCIO} (V)												Unit
		1.2		1.5		1.8		2.5		3.0		3.3		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus hold low, sustaining current	$V_{IN} > V_{IL}$ (maximum)	8	—	12	—	30	—	50	—	70	—	70	—	µA
Bus hold high, sustaining current	$V_{IN} < V_{IL}$ (minimum)	–8	—	–12	—	–30	—	–50	—	–70	—	–70	—	µA
Bus hold low, overdrive current	0 V < V_{IN} < V_{CCIO}	—	125	—	175	—	200	—	300	—	500	—	500	µA
Bus hold high, overdrive current	0 V < V_{IN} < V_{CCIO}	—	–125	—	–175	—	–200	—	–300	—	–500	—	–500	µA

Table 1–7. Bus Hold Parameter for Cyclone IV Devices (Part 2 of 2) *(1)*

Parameter	Condition	V_{CCIO} (V)												Unit
		1.2		1.5		1.8		2.5		3.0		3.3		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus hold trip point	—	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V

Note to Table 1–7:

(1) Bus hold trip points are based on the calculated input voltages from the JEDEC standard.

OCT Specifications

Table 1–8 lists the variation of OCT without calibration across process, temperature, and voltage (PVT).

Table 1–8. Series OCT Without Calibration Specifications for Cyclone IV Devices

Description	V_{CCIO} (V)	Resistance Tolerance		Unit
		Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	
Series OCT without calibration	3.0	±30	±40	%
	2.5	±30	±40	%
	1.8	±40	±50	%
	1.5	±50	±50	%
	1.2	±50	±50	%

OCT calibration is automatically performed at device power-up for OCT-enabled I/Os.

Table 1–9 lists the OCT calibration accuracy at device power-up.

Table 1–9. Series OCT with Calibration at Device Power-Up Specifications for Cyclone IV Devices

Description	V_{CCIO} (V)	Calibration Accuracy		Unit
		Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	
Series OCT with calibration at device power-up	3.0	±10	±10	%
	2.5	±10	±10	%
	1.8	±10	±10	%
	1.5	±10	±10	%
	1.2	±10	±10	%

The OCT resistance may vary with the variation of temperature and voltage after calibration at device power-up. Use Table 1–10 and Equation 1–1 to determine the final OCT resistance considering the variations after calibration at device power-up. Table 1–10 lists the change percentage of the OCT resistance with voltage and temperature.

Table 1–10. OCT Variation After Calibration at Device Power-Up for Cyclone IV Devices

Nominal Voltage	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.262	–0.026
2.5	0.234	–0.039
1.8	0.219	–0.086
1.5	0.199	–0.136
1.2	0.161	–0.288

Equation 1–1. Final OCT Resistance *(1), (2), (3), (4), (5), (6)*

$\Delta R_V = (V_2 - V_1) \times 1000 \times dR/dV$ —— *(7)*

$\Delta R_T = (T_2 - T_1) \times dR/dT$ —— *(8)*

For $\Delta R_x < 0$; $MF_x = 1/(|\Delta R_x|/100 + 1)$ —— *(9)*

For $\Delta R_x > 0$; $MF_x = \Delta R_x/100 + 1$ —— *(10)*

$MF = MF_V \times MF_T$ —— *(11)*

$R_{final} = R_{initial} \times MF$ —— *(12)*

Notes to Equation 1–1:

(1) T_2 is the final temperature.
(2) T_1 is the initial temperature.
(3) MF is multiplication factor.
(4) R_{final} is final resistance.
(5) $R_{initial}$ is initial resistance.
(6) Subscript $_x$ refers to both $_V$ and $_T$.
(7) ΔR_V is a variation of resistance with voltage.
(8) ΔR_T is a variation of resistance with temperature.
(9) dR/dT is the change percentage of resistance with temperature after calibration at device power-up.
(10) dR/dV is the change percentage of resistance with voltage after calibration at device power-up.
(11) V_2 is final voltage.
(12) V_1 is the initial voltage.

Internal Weak Pull-Up and Weak Pull-Down Resistor

Table 1–12 lists the weak pull-up and pull-down resistor values for Cyclone IV devices.

Table 1–12. Internal Weak Pull-Up and Weak Pull-Down Resistor Values for Cyclone IV Devices *(1)*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{\_PU}$	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option	V_{CCIO} = 3.3 V ± 5% *(2), (3)*	7	25	41	kΩ
		V_{CCIO} = 3.0 V ± 5% *(2), (3)*	7	28	47	kΩ
		V_{CCIO} = 2.5 V ± 5% *(2), (3)*	8	35	61	kΩ
		V_{CCIO} = 1.8 V ± 5% *(2), (3)*	10	57	108	kΩ
		V_{CCIO} = 1.5 V ± 5% *(2), (3)*	13	82	163	kΩ
		V_{CCIO} = 1.2 V ± 5% *(2), (3)*	19	143	351	kΩ
$R_{\_PD}$	Value of the I/O pin pull-down resistor before and during configuration	V_{CCIO} = 3.3 V ± 5% *(4)*	6	19	30	kΩ
		V_{CCIO} = 3.0 V ± 5% *(4)*	6	22	36	kΩ
		V_{CCIO} = 2.5 V ± 5% *(4)*	6	25	43	kΩ
		V_{CCIO} = 1.8 V ± 5% *(4)*	7	35	71	kΩ
		V_{CCIO} = 1.5 V ± 5% *(4)*	8	50	112	kΩ

Notes to Table 1–12:

(1) All I/O pins have an option to enable weak pull-up except the configuration, test, and JTAG pins. The weak pull-down feature is only available for JTAG `TCK`.

(2) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.

(3) $R_{\_PU} = (V_{CCIO} - V_I)/I_{R\_PU}$
Minimum condition: –40°C; $V_{CCIO} = V_{CC} + 5\%$, $V_I = V_{CC} + 5\% - 50$ mV;
Typical condition: 25°C; $V_{CCIO} = V_{CC}$, $V_I = 0$ V;
Maximum condition: 100°C; $V_{CCIO} = V_{CC} - 5\%$, $V_I = 0$ V; in which V_I refers to the input voltage at the I/O pin.

(4) $R_{\_PD} = V_I/I_{R\_PD}$
Minimum condition: –40°C; $V_{CCIO} = V_{CC} + 5\%$, $V_I = 50$ mV;
Typical condition: 25°C; $V_{CCIO} = V_{CC}$, $V_I = V_{CC} - 5\%$;
Maximum condition: 100°C; $V_{CCIO} = V_{CC} - 5\%$, $V_I = V_{CC} - 5\%$; in which V_I refers to the input voltage at the I/O pin.

Hot-Socketing

Table 1–13 lists the hot-socketing specifications for Cyclone IV devices.

Table 1–13. Hot-Socketing Specifications for Cyclone IV Devices

Symbol	Parameter	Maximum
$I_{IOPIN(DC)}$	DC current per I/O pin	300 μA
$I_{IOPIN(AC)}$	AC current per I/O pin	8 mA *(1)*
$I_{XCVRTX(DC)}$	DC current per transceiver `TX` pin	100 mA
$I_{XCVRRX(DC)}$	DC current per transceiver `RX` pin	50 mA

Note to Table 1–13:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, |IIOPIN| = C dv/dt, in which C is the I/O pin capacitance and dv/dt is the slew rate.

☞ During hot-socketing, the I/O pin capacitance is less than 15 pF and the clock pin capacitance is less than 20 pF.

Table 1–16. Single-Ended SSTL and HSTL I/O Reference Voltage Specifications for Cyclone IV Devices *(1)*

I/O Standard	V_{CCIO} (V)			V_{REF} (V)			V_{TT} (V) *(2)*		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	1.19	1.25	1.31	V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04
SSTL-18 Class I, II	1.7	1.8	1.9	0.833	0.9	0.969	V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	0.85	0.9	0.95
HSTL-15 Class I, II	1.425	1.5	1.575	0.71	0.75	0.79	0.71	0.75	0.79
HSTL-12 Class I, II	1.14	1.2	1.26	0.48 x V_{CCIO} *(3)* 0.47 x V_{CCIO} *(4)*	0.5 x V_{CCIO} *(3)* 0.5 x V_{CCIO} *(4)*	0.52 x V_{CCIO} *(3)* 0.53 x V_{CCIO} *(4)*	—	0.5 x V_{CCIO}	—

Notes to Table 1–16:

(1) For an explanation of terms used in Table 1–16, refer to "Glossary" on page 1–37.

(2) V_{TT} of the transmitting device must track V_{REF} of the receiving device.

(3) Value shown refers to DC input reference voltage, $V_{REF(DC)}$.

(4) Value shown refers to AC input reference voltage, $V_{REF(AC)}$.

Table 1–17. Single-Ended SSTL and HSTL I/O Standards Signal Specifications for Cyclone IV Devices

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)		$V_{IH(AC)}$ (V)		V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Max	Min	Max	Min	Max	Min	Max	Max	Min		
SSTL-2 Class I	—	V_{REF} – 0.18	V_{REF} + 0.18	—	—	V_{REF} – 0.35	V_{REF} + 0.35	—	V_{TT} – 0.57	V_{TT} + 0.57	8.1	–8.1
SSTL-2 Class II	—	V_{REF} – 0.18	V_{REF} + 0.18	—	—	V_{REF} – 0.35	V_{REF} + 0.35	—	V_{TT} – 0.76	V_{TT} + 0.76	16.4	–16.4
SSTL-18 Class I	—	V_{REF} – 0.125	V_{REF} + 0.125	—	—	V_{REF} – 0.25	V_{REF} + 0.25	—	V_{TT} – 0.475	V_{TT} + 0.475	6.7	–6.7
SSTL-18 Class II	—	V_{REF} – 0.125	V_{REF} + 0.125	—	—	V_{REF} – 0.25	V_{REF} + 0.25	—	0.28	V_{CCIO} – 0.28	13.4	–13.4
HSTL-18 Class I	—	V_{REF} – 0.1	V_{REF} + 0.1	—	—	V_{REF} – 0.2	V_{REF} + 0.2	—	0.4	V_{CCIO} – 0.4	8	–8
HSTL-18 Class II	—	V_{REF} – 0.1	V_{REF} + 0.1	—	—	V_{REF} – 0.2	V_{REF} + 0.2	—	0.4	V_{CCIO} – 0.4	16	–16
HSTL-15 Class I	—	V_{REF} – 0.1	V_{REF} + 0.1	—	—	V_{REF} – 0.2	V_{REF} + 0.2	—	0.4	V_{CCIO} – 0.4	8	–8
HSTL-15 Class II	—	V_{REF} – 0.1	V_{REF} + 0.1	—	—	V_{REF} – 0.2	V_{REF} + 0.2	—	0.4	V_{CCIO} – 0.4	16	–16
HSTL-12 Class I	–0.15	V_{REF} – 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	–0.24	V_{REF} – 0.15	V_{REF} + 0.15	V_{CCIO} + 0.24	0.25 × V_{CCIO}	0.75 × V_{CCIO}	8	–8
HSTL-12 Class II	–0.15	V_{REF} – 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	–0.24	V_{REF} – 0.15	V_{REF} + 0.15	V_{CCIO} + 0.24	0.25 × V_{CCIO}	0.75 × V_{CCIO}	14	–14

For more information about receiver input and transmitter output waveforms, and for other differential I/O standards, refer to the *I/O Features in Cyclone IV Devices* chapter.

Table 1–18. Differential SSTL I/O Standard Specifications for Cyclone IV Devices *(1)*

I/O Standard	V_{CCIO} (V)			$V_{Swing(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{Swing(AC)}$ (V)		$V_{OX(AC)}$ (V)		
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.36	V_{CCIO}	V_{CCIO}/2 – 0.2	—	V_{CCIO}/2 + 0.2	0.7	V_{CCIO}	V_{CCIO}/2 – 0.125	—	V_{CCIO}/2 + 0.125
SSTL-18 Class I, II	1.7	1.8	1.90	0.25	V_{CCIO}	V_{CCIO}/2 – 0.175	—	V_{CCIO}/2 + 0.175	0.5	V_{CCIO}	V_{CCIO}/2 – 0.125	—	V_{CCIO}/2 + 0.125

Note to Table 1–18:

(1) Differential SSTL requires a V_{REF} input.

Table 1–19. Differential HSTL I/O Standard Specifications for Cyclone IV Devices *(1)*

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	—	0.85	—	0.95	0.85	—	0.95	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.71	—	0.79	0.71	—	0.79	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V_{CCIO}	0.48 x V_{CCIO}	—	0.52 x V_{CCIO}	0.48 x V_{CCIO}	—	0.52 x V_{CCIO}	0.3	0.48 x V_{CCIO}

Note to Table 1–19:

(1) Differential HSTL requires a V_{REF} input.

Table 1–20. Differential I/O Standard Specifications for Cyclone IV Devices *(1)* **(Part 1 of 2)**

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)		V_{IcM} (V) *(2)*			V_{OD} (mV) *(3)*			V_{OS} (V) *(3)*		
	Min	Typ	Max	Min	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
LVPECL (Row I/Os) *(6)*	2.375	2.5	2.625	100	—	0.05	D_{MAX} ≤ 500 Mbps	1.80	—	—	—	—	—	—
						0.55	500 Mbps ≤ D_{MAX} ≤ 700 Mbps	1.80						
						1.05	D_{MAX} > 700 Mbps	1.55						
LVPECL (Column I/Os) *(6)*	2.375	2.5	2.625	100	—	0.05	D_{MAX} ≤ 500 Mbps	1.80	—	—	—	—	—	—
						0.55	500 Mbps ≤ D_{MAX} ≤ 700 Mbps	1.80						
						1.05	D_{MAX} > 700 Mbps	1.55						
LVDS (Row I/Os)	2.375	2.5	2.625	100	—	0.05	D_{MAX} ≤ 500 Mbps	1.80	247	—	600	1.125	1.25	1.375
						0.55	500 Mbps ≤ D_{MAX} ≤ 700 Mbps	1.80						
						1.05	D_{MAX} > 700 Mbps	1.55						

Table 1–20. Differential I/O Standard Specifications for Cyclone IV Devices *(1)* **(Part 2 of 2)**

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)		V_{IcM} (V) *(2)*			V_{OD} (mV) *(3)*			V_{OS} (V) *(3)*		
	Min	**Typ**	**Max**	**Min**	**Max**	**Min**	**Condition**	**Max**	**Min**	**Typ**	**Max**	**Min**	**Typ**	**Max**
LVDS (Column I/Os)	2.375	2.5	2.625	100	—	0.05	$D_{MAX} \leq$ 500 Mbps	1.80	247	—	600	1.125	1.25	1.375
						0.55	500 Mbps $\leq D_{MAX} \leq$ 700 Mbps	1.80						
						1.05	D_{MAX} > 700 Mbps	1.55						
BLVDS (Row I/Os) *(4)*	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—
BLVDS (Column I/Os) *(4)*	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—
mini-LVDS (Row I/Os) *(5)*	2.375	2.5	2.625	—	—	—	—	—	300	—	600	1.0	1.2	1.4
mini-LVDS (Column I/Os) *(5)*	2.375	2.5	2.625	—	—	—	—	—	300	—	600	1.0	1.2	1.4
RSDS® (Row I/Os) *(5)*	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.5
RSDS (Column I/Os) *(5)*	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.5
PPDS (Row I/Os) *(5)*	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.4
PPDS (Column I/Os) *(5)*	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.4

Notes to Table 1–20:

(1) For an explanation of terms used in Table 1–20, refer to “Glossary” on page 1–37.

(2) V_{IN} range: 0 V $\leq V_{IN} \leq$ 1.85 V.

(3) R_L range: 90 $\leq R_L \leq$ 110 Ω.

(4) There are no fixed V_{IN}, V_{OD}, and V_{OS} specifications for BLVDS. They depend on the system topology.

(5) The Mini-LVDS, RSDS, and PPDS standards are only supported at the output pins.

(6) The LVPECL I/O standard is only supported on dedicated clock input pins. This I/O standard is not supported for output pins.

Transceiver Performance Specifications

Table 1–21 lists the Cyclone IV GX transceiver specifications.

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 1 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Reference Clock											
Supported I/O Standards	1.2 V PCML, 1.5 V PCML, 3.3 V PCML, Differential LVPECL, LVDS, HCSL										
Input frequency from `REFCLK` input pins	—	50	—	156.25	50	—	156.25	50	—	156.25	MHz
Spread-spectrum modulating clock frequency	Physical interface for PCI Express (PIPE) mode	30	—	33	30	—	33	30	—	33	kHz
Spread-spectrum downspread	PIPE mode	—	0 to –0.5%	—	—	0 to –0.5%	—	—	0 to –0.5%	—	—
Peak-to-peak differential input voltage	—	0.1	—	1.6	0.1	—	1.6	0.1	—	1.6	V
V_{ICM} (AC coupled)	—	1100 ± 5%			1100 ± 5%			1100 ± 5%			mV
V_{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	250	—	550	mV
Transmitter REFCLK Phase Noise *(1)*	Frequency offset = 1 MHz – 8 MHZ	—	—	–123	—	—	–123	—	—	–123	dBc/Hz
Transmitter REFCLK Total Jitter *(1)*		—	—	42.3	—	—	42.3	—	—	42.3	ps
R_{ref}	—	—	2000 ± 1%	—	—	2000 ± 1%	—	—	2000 ± 1%	—	Ω
Transceiver Clock											
`cal_blk_clk` clock frequency	—	10	—	125	10	—	125	10	—	125	MHz
`fixedclk` clock frequency	PCIe Receiver Detect	—	125	—	—	125	—	—	125	—	MHz
`reconfig_clk` clock frequency	Dynamic reconfiguration clock frequency	2.5/ 37.5 *(2)*	—	50	2.5/ 37.5 *(2)*	—	50	2.5/ 37.5 *(2)*	—	50	MHz
Delta time between `reconfig_clk`	—	—	—	2	—	—	2	—	—	2	ms
Transceiver block minimum power-down pulse width	—	—	1	—	—	1	—	—	1	—	µs

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 2 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Receiver											
Supported I/O Standards	1.4 V PCML, 1.5 V PCML, 2.5 V PCML, LVPECL, LVDS										
Data rate (F324 and smaller package) *(15)*	—	600	—	2500	600	—	2500	600	—	2500	Mbps
Data rate (F484 and larger package) *(15)*	—	600	—	3125	600	—	3125	600	—	2500	Mbps
Absolute V_{MAX} for a receiver pin *(3)*	—	—	—	1.6	—	—	1.6	—	—	1.6	V
Operational V_{MAX} for a receiver pin	—	—	—	1.5	—	—	1.5	—	—	1.5	V
Absolute V_{MIN} for a receiver pin	—	–0.4	—	—	–0.4	—	—	–0.4	—	—	V
Peak-to-peak differential input voltage V_{ID} (diff p-p)	V_{ICM} = 0.82 V setting, Data Rate = 600 Mbps to 3.125 Gbps	0.1	—	2.7	0.1	—	2.7	0.1	—	2.7	V
V_{ICM}	V_{ICM} = 0.82 V setting	—	820 ± 10%	—	—	820 ± 10%	—	—	820 ± 10%	—	mV
Differential on-chip termination resistors	100–Ω setting	—	100	—	—	100	—	—	100	—	Ω
	150–Ω setting	—	150	—	—	150	—	—	150	—	Ω
Differential and common mode return loss	PIPE, Serial Rapid I/O SR, SATA, CPRI LV, SDI, XAUI	Compliant									—
Programmable ppm detector *(4)*	—	± 62.5, 100, 125, 200, 250, 300									ppm
Clock data recovery (CDR) ppm tolerance (without spread-spectrum clocking enabled)	—	—	—	±300 *(5)*, ±350 *(6)*, *(7)*	—	—	±300 *(5)*, ±350 *(6)*, *(7)*	—	—	±300 *(5)*, ±350 *(6)*, *(7)*	ppm
CDR ppm tolerance (with synchronous spread-spectrum clocking enabled) *(8)*	—	—	—	350 to –5350 *(7)*, *(9)*	—	—	350 to –5350 *(7)*, *(9)*	—	—	350 to –5350 *(7)*, *(9)*	ppm
Run length	—	—	80	—	—	80	—	—	80	—	UI
Programmable equalization	No Equalization	—	—	1.5	—	—	1.5	—	—	1.5	dB
	Medium Low	—	—	4.5	—	—	4.5	—	—	4.5	dB
	Medium High	—	—	5.5	—	—	5.5	—	—	5.5	dB
	High	—	—	7	—	—	7	—	—	7	dB

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 3 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Signal detect/loss threshold	PIPE mode	65	—	175	65	—	175	65	—	175	mV
t_{LTR} *(10)*	—	—	—	75	—	—	75	—	—	75	µs
$t_{LTR\text{-}LTD\_Manual}$ *(11)*	—	15	—	—	15	—	—	15	—	—	µs
t_{LTD} *(12)*	—	0	100	4000	0	100	4000	0	100	4000	ns
t_{LTD_Manual} *(13)*	—	—	—	4000	—	—	4000	—	—	4000	ns
t_{LTD_Auto} *(14)*	—	—	—	4000	—	—	4000	—	—	4000	ns
Receiver buffer and CDR offset cancellation time (per channel)	—	—	—	17000	—	—	17000	—	—	17000	`reconfig_clk` cycles
Programmable DC gain	DC Gain Setting = 0	—	0	—	—	0	—	—	0	—	dB
	DC Gain Setting = 1	—	3	—	—	3	—	—	3	—	dB
	DC Gain Setting = 2	—	6	—	—	6	—	—	6	—	dB
Transmitter											
Supported I/O Standards	1.5 V PCML										
Data rate (F324 and smaller package)	—	600	—	2500	600	—	2500	600	—	2500	Mbps
Data rate (F484 and larger package)	—	600	—	3125	600	—	3125	600	—	2500	Mbps
V_{OCM}	0.65 V setting	—	650	—	—	650	—	—	650	—	mV
Differential on-chip termination resistors	100–Ω setting	—	100	—	—	100	—	—	100	—	Ω
	150–Ω setting	—	150	—	—	150	—	—	150	—	Ω
Differential and common mode return loss	PIPE, CPRI LV, Serial Rapid I/O SR, SDI, XAUI, SATA	Compliant									—
Rise time	—	50	—	200	50	—	200	50	—	200	ps
Fall time	—	50	—	200	50	—	200	50	—	200	ps
Intra-differential pair skew	—	—	—	15	—	—	15	—	—	15	ps
Intra-transceiver block skew	—	—	—	120	—	—	120	—	—	120	ps

Table 1–24. Clock Tree Performance for Cyclone IV Devices *(Part 2 of 2)*

Device	**Performance**								**Unit**
	C6	**C7**	**C8**	**C8L** *(1)*	**C9L** *(1)*	**I7**	**I8L** *(1)*	**A7**	
EP4CE55	500	437.5	402	362	265	437.5	362	—	MHz
EP4CE75	500	437.5	402	362	265	437.5	362	—	MHz
EP4CE115	—	437.5	402	362	265	437.5	362	—	MHz
EP4CGX15	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX22	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX30	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX50	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX75	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX110	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX150	500	437.5	402	—	—	437.5	—	—	MHz

Note to Table 1–24:

(1) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades.

PLL Specifications

Table 1–25 lists the PLL specifications for Cyclone IV devices when operating in the commercial junction temperature range (0°C to 85°C), the industrial junction temperature range (–40°C to 100°C), the extended industrial junction temperature range (–40°C to 125°C), and the automotive junction temperature range (–40°C to 125°C). For more information about the PLL block, refer to “Glossary” on page 1–37.

Table 1–25. PLL Specifications for Cyclone IV Devices *(1), (2)* **(Part 1 of 2)**

Symbol	**Parameter**	**Min**	**Typ**	**Max**	**Unit**
f_{IN} *(3)*	Input clock frequency (–6, –7, –8 speed grades)	5	—	472.5	MHz
	Input clock frequency (–8L speed grade)	5	—	362	MHz
	Input clock frequency (–9L speed grade)	5	—	265	MHz
f_{INPFD}	PFD input frequency	5	—	325	MHz
f_{VCO} *(4)*	PLL internal VCO operating range	600	—	1300	MHz
f_{INDUTY}	Input clock duty cycle	40	—	60	%
$t_{INJITTER\_CCJ}$ *(5)*	Input clock cycle-to-cycle jitter $F_{REF} \geq 100$ MHz	—	—	0.15	UI
	$F_{REF} < 100$ MHz	—	—	±750	ps
f_{OUT_EXT} (external clock output) *(3)*	PLL output frequency	—	—	472.5	MHz
f_{OUT} (to global clock)	PLL output frequency (–6 speed grade)	—	—	472.5	MHz
	PLL output frequency (–7 speed grade)	—	—	450	MHz
	PLL output frequency (–8 speed grade)	—	—	402.5	MHz
	PLL output frequency (–8L speed grade)	—	—	362	MHz
	PLL output frequency (–9L speed grade)	—	—	265	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output (when set to 50%)	45	50	55	%
t_{LOCK}	Time required to lock from end of device configuration	—	—	1	ms

For more information about the supported maximum clock rate, device and pin planning, IP implementation, and device termination, refer to *Section III: System Performance Specifications* of the *External Memory Interfaces Handbook*.

Actual achievable frequency depends on design- and system-specific factors. Perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specifications

Table 1–31 through Table 1–36 list the high-speed I/O timing for Cyclone IV devices. For definitions of high-speed timing specifications, refer to "Glossary" on page 1–37.

Table 1–31. RSDS Transmitter Timing Specifications for Cyclone IV Devices (1), (2), (4) (Part 1 of 2)

Symbol	Modes	C6			C7, I7			C8, A7			C8L, I8L			C9L			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f_{HSCLK} (input clock frequency)	×10	5	—	180	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×8	5	—	180	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×7	5	—	180	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×4	5	—	180	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×2	5	—	180	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×1	5	—	360	5	—	311	5	—	311	5	—	311	5	—	265	MHz
Device operation in Mbps	×10	100	—	360	100	—	311	100	—	311	100	—	311	100	—	265	Mbps
	×8	80	—	360	80	—	311	80	—	311	80	—	311	80	—	265	Mbps
	×7	70	—	360	70	—	311	70	—	311	70	—	311	70	—	265	Mbps
	×4	40	—	360	40	—	311	40	—	311	40	—	311	40	—	265	Mbps
	×2	20	—	360	20	—	311	20	—	311	20	—	311	20	—	265	Mbps
	×1	10	—	360	10	—	311	10	—	311	10	—	311	10	—	265	Mbps
t_{DUTY}	—	45	—	55	45	—	55	45	—	55	45	—	55	45	—	55	%
Transmitter channel-to-channel skew (TCCS)	—	—	—	200	—	—	200	—	—	200	—	—	200	—	—	200	ps
Output jitter (peak to peak)	—	—	—	500	—	—	500	—	—	550	—	—	600	—	—	700	ps
t_{RISE}	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	—	500	—	—	500	—	ps
t_{FALL}	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	—	500	—	—	500	—	ps

Table 1–44 and Table 1–45 list the IOE programmable delay for Cyclone IV GX devices.

Table 1–44. IOE Programmable Delay on Column Pins for Cyclone IV GX Devices (1), (2)

Parameter	Paths Affected	Number of Settings	Min Offset	Max Offset						Unit
				Fast Corner		Slow Corner				
				C6	I7	C6	C7	C8	I7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.313	1.209	2.184	2.336	2.451	2.387	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.312	1.208	2.200	2.399	2.554	2.446	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.438	0.404	0.751	0.825	0.886	0.839	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.713	0.682	1.228	1.41	1.566	1.424	ns

Notes to Table 1–44:

(1) The incremental values for the settings are generally linear. For exact values of each setting, use the latest version of the Quartus II software.

(2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

Table 1–45. IOE Programmable Delay on Row Pins for Cyclone IV GX Devices (1), (2)

Parameter	Paths Affected	Number of Settings	Min Offset	Max Offset						Unit
				Fast Corner		Slow Corner				
				C6	I7	C6	C7	C8	I7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.314	1.210	2.209	2.398	2.526	2.443	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.313	1.208	2.205	2.406	2.563	2.450	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.461	0.421	0.789	0.869	0.933	0.884	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.712	0.682	1.225	1.407	1.562	1.421	ns

Notes to Table 1–45:

(1) The incremental values for the settings are generally linear. For exact values of each setting, use the latest version of Quartus II software.

(2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software

Table 1–46. Glossary (Part 2 of 5)

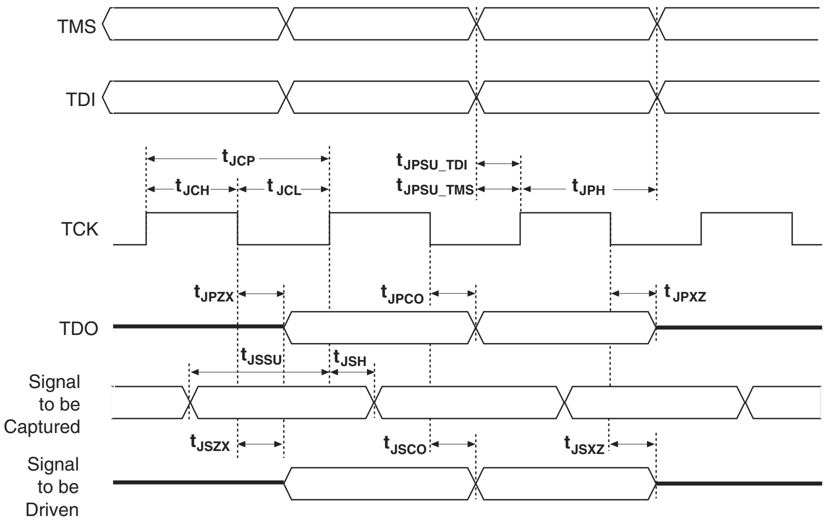
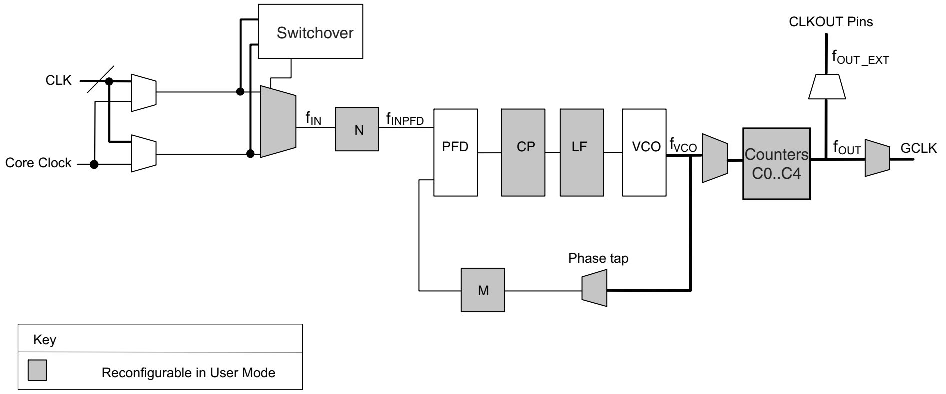
Letter	Term	Definitions
J	JTAG Waveform	
K	—	—
L	—	—
M	—	—
N	—	—
O	—	—
P	PLL Block	The following highlights the PLL specification parameters: 
Q	—	—

Table 1–46. Glossary (Part 3 of 5)

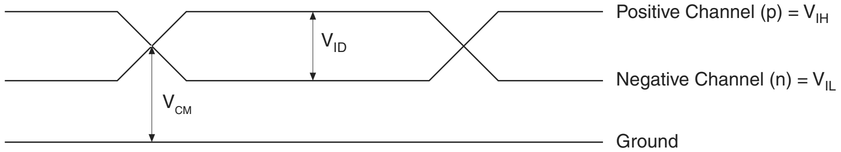
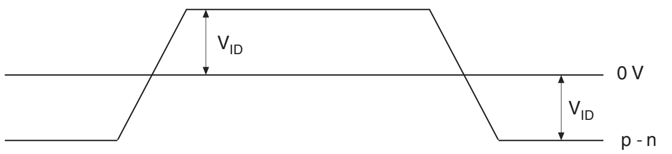
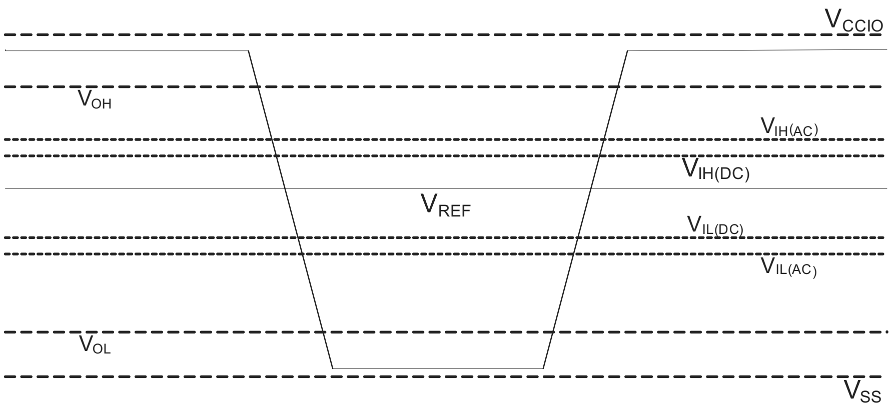
Letter	Term	Definitions
R	R_L	Receiver differential input discrete resistor (external to Cyclone IV devices).
	Receiver Input Waveform	Receiver input waveform for LVDS and LVPECL differential standards: **Single-Ended Waveform**  **Differential Waveform (Mathematical Function of Positive & Negative Channel)** 
	Receiver input skew margin (RSKM)	High-speed I/O block: The total margin left after accounting for the sampling window and TCCS. RSKM = (TUI – SW – TCCS) / 2.
S	Single-ended voltage-referenced I/O Standard	 The JEDEC standard for SSTl and HSTL I/O standards defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input crosses the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform *ringing*.
	SW (Sampling Window)	High-speed I/O block: The period of time during which the data must be valid to capture it correctly. The setup and hold times determine the ideal strobe position in the sampling window.

Table 1–46. Glossary (Part 5 of 5)

Letter	Term	Definitions
V	$V_{CM(DC)}$	DC common mode input voltage.
	$V_{DIF(AC)}$	AC differential input voltage: The minimum AC input differential voltage required for switching.
	$V_{DIF(DC)}$	DC differential input voltage: The minimum DC input differential voltage required for switching.
	V_{ICM}	Input common mode voltage: The common mode of the differential signal at the receiver.
	V_{ID}	Input differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.
	V_{IH}	Voltage input high: The minimum positive voltage applied to the input that is accepted by the device as a logic high.
	$V_{IH(AC)}$	High-level AC input voltage.
	$V_{IH(DC)}$	High-level DC input voltage.
	V_{IL}	Voltage input low: The maximum positive voltage applied to the input that is accepted by the device as a logic low.
	$V_{IL\ (AC)}$	Low-level AC input voltage.
	$V_{IL\ (DC)}$	Low-level DC input voltage.
	V_{IN}	DC input voltage.
	V_{OCM}	Output common mode voltage: The common mode of the differential signal at the transmitter.
	V_{OD}	Output differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter. $V_{OD} = V_{OH} – V_{OL}$.
	V_{OH}	Voltage output high: The maximum positive voltage from an output that the device considers is accepted as the minimum positive high level.
	V_{OL}	Voltage output low: The maximum positive voltage from an output that the device considers is accepted as the maximum positive low level.
	V_{OS}	Output offset voltage: $V_{OS} = (V_{OH} + V_{OL}) / 2$.
	$V_{OX\ (AC)}$	AC differential output cross point voltage: the voltage at which the differential output signals must cross.
	V_{REF}	Reference voltage for the SSTL and HSTL I/O standards.
	$V_{REF\ (AC)}$	AC input reference voltage for the SSTL and HSTL I/O standards. $V_{REF(AC)} = V_{REF(DC)}$ + noise. The peak-to-peak AC noise on V_{REF} must not exceed 2% of $V_{REF(DC)}$.
	$V_{REF\ (DC)}$	DC input reference voltage for the SSTL and HSTL I/O standards.
	$V_{SWING\ (AC)}$	AC differential input voltage: AC input differential voltage required for switching. For the SSTL differential I/O standard, refer to Input Waveforms.
	$V_{SWING\ (DC)}$	DC differential input voltage: DC input differential voltage required for switching. For the SSTL differential I/O standard, refer to Input Waveforms.
	V_{TT}	Termination voltage for the SSTL and HSTL I/O standards.
	$V_{X\ (AC)}$	AC differential input cross point voltage: The voltage at which the differential input signals must cross.
W	—	—
X	—	—
Y	—	—
Z	—	—

Document Revision History

Table 1–47 lists the revision history for this chapter.

Table 1–47. Document Revision History

Date	Version	Changes
March 2016	2.0	Updated note (5) in Table 1–21 to remove support for the N148 package.
October 2014	1.9	Updated maximum value for V_{CCD_PLL} in Table 1–1. Removed extended temperature note in Table 1–3.
December 2013	1.8	Updated Table 1–21 by adding Note (15).
May 2013	1.7	Updated Table 1–15 by adding Note (4).
October 2012	1.6	■ Updated the maximum value for V_I, V_{CCD_PLL}, V_{CCIO}, V_{CC_CLKIN}, V_{CCH_GXB}, and V_{CCA_GXB} Table 1–1. ■ Updated Table 1–11 and Table 1–22. ■ Updated Table 1–21 to include peak-to-peak differential input voltage for the Cyclone IV GX transceiver input reference clock. ■ Updated Table 1–29 to include the typical `DCLK` value. ■ Updated the minimum f_{HSCLK} value in Table 1–31, Table 1–32, Table 1–33, Table 1–34, and Table 1–35.
November 2011	1.5	■ Updated “Maximum Allowed Overshoot or Undershoot Voltage”, “Operating Conditions”, and “PLL Specifications” sections. ■ Updated Table 1–2, Table 1–3, Table 1–4, Table 1–5, Table 1–8, Table 1–9, Table 1–15, Table 1–18, Table 1–19, and Table 1–21. ■ Updated Figure 1–1.
December 2010	1.4	■ Updated for the Quartus II software version 10.1 release. ■ Updated Table 1–21 and Table 1–25. ■ Minor text edits.
July 2010	1.3	Updated for the Quartus II software version 10.0 release: ■ Updated Table 1–3, Table 1–4, Table 1–21, Table 1–25, Table 1–28, Table 1–30, Table 1–40, Table 1–41, Table 1–42, Table 1–43, Table 1–44, and Table 1–45. ■ Updated Figure 1–2 and Figure 1–3. ■ Removed SW Requirement and TCCS for Cyclone IV Devices tables. ■ Minor text edits.
March 2010	1.2	Updated to include automotive devices: ■ Updated the “Operating Conditions” and “PLL Specifications” sections. ■ Updated Table 1–1, Table 1–8, Table 1–9, Table 1–21, Table 1–26, Table 1–27, Table 1–31, Table 1–32, Table 1–33, Table 1–34, Table 1–35, Table 1–36, Table 1–37, Table 1–38, Table 1–40, Table 1–42, and Table 1–43. ■ Added Table 1–5 to include ESD for Cyclone IV devices GPIOs and HSSI I/Os. ■ Added Table 1–44 and Table 1–45 to include IOE programmable delay for Cyclone IV E 1.2 V core voltage devices. ■ Minor text edits.